

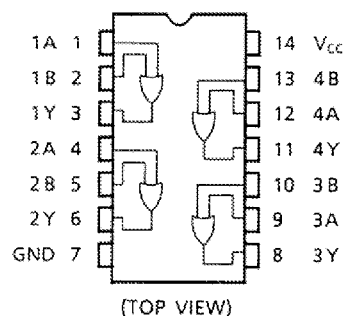
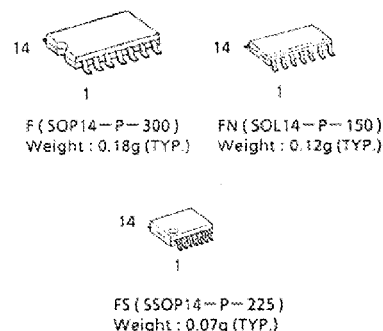
QUAD 2 - Input OR Gate

The TC74LVQ32 is a high speed CMOS 2-INPUT OR GATE fabricated with silicon gate and double-layer metal wiring C²MOS technology.

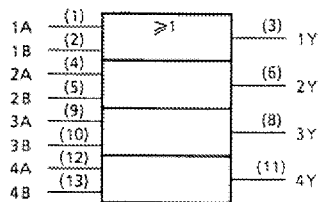
Designed for use in 3.3 Volt systems, it achieves high speed operation while maintaining the CMOS low power dissipation. The internal circuit is composed of 2 stages including buffer output, which provide high noise immunity and stable output. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High Speed: $t_{pd} = 4.1 \text{ ns}$ (Typ.) at $V_{CC} = 3.3\text{V}$
- Low Power Dissipation: $I_{CC} = 2.5 \mu\text{A}$ (Max.) at $T_a = 25^\circ\text{C}$
- Input Voltage Level:
 - $V_{IL} = 0.8\text{V}$ (Max.) at $V_{CC} = 3\text{V}$
 - $V_{IH} = 2.0\text{V}$ (Min.) at $V_{CC} = 3\text{V}$
- Symmetrical Output Impedance: $|I_{OH}| = I_{OL} = 12\text{mA}$ (Min.)
- Balanced Propagation Delays: $t_{pLH} = t_{pHL}$
- Pin and Function Compatible with 74HC32



Pin Assignment



IEC Logic Symbol

Truth Table

Inputs		Outputs
A	B	Y
L	L	L
L	H	H
H	L	H
H	H	H

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Supply Voltage Range	V_{CC}	-0.5 ~ 7.0	V
DC Input Voltage	V_{IN}	-0.5 ~ $V_{CC} + 0.5$	V
DC Output Voltage	V_{OUT}	-0.5 ~ $V_{CC} + 0.5$	V
Input Diode Current	I_{IK}	±20	mA
Output Diode Current	I_{OK}	±50	mA
DC Output Current	I_{OUT}	±50	mA
DC V_{CC} /Ground Current	I_{CC}	±100	mA
Power Dissipation	P_D	180	mW
Storage Temperature	T_{stg}	-65 ~ 150	°C
Lead Temperature 10sec	T_L	300	°C

Recommended Operating Conditions

Parameter	Symbol	Value	Unit
Supply Voltage	V_{CC}	2.0 ~ 3.6	V
Input Voltage	V_{IN}	0 ~ V_{CC}	V
Output Voltage	V_{OUT}	0 ~ V_{CC}	V
Operating Temperature	T_{opr}	-40 ~ 85	°C
Input Rise and Fall Time	dt/dv	0 ~ 100	ns/V

DC Electrical Characteristics

Parameter	Symbol	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40 \sim 85^\circ\text{C}$		Unit		
			V_{CC} (V)	Min	Typ.	Max.	Min.		Max.	
High-Level Input Voltage	V_{IH}	–	3.0	2.0	–	–	2.0	–	V	
Low-Level Input Voltage	V_{IL}	–	3.0	–	–	0.8	–	0.8		
High-Level Output Voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50\mu\text{A}$	3.0	2.9	3.0	–	2.9		–
			$I_{OH} = -12\text{mA}$	3.0	2.58	–	–	2.48		–
Low-Level Output Voltage	V_{OL}	$V_{IN} = V_{IL}$	$I_{OL} = 50\mu\text{A}$	3.0	–	0.0	0.1	–	0.1	
			$I_{OL} = 12\text{mA}$	3.0	–	–	0.36	–	0.44	
Input Leakage Current	I_{IN}	$V_{IN} = V_{CC}$ or GND	3.6	–	–	±0.1	–	±1.0	μA	
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND	3.6	–	–	2.5	–	25.0		

AC Electrical Characteristics (Input $t_r = t_f = 3\text{ns}$, $C_L = 50\text{pF}$, $R_L = 500\Omega$)

Parameter	Symbol	Test Condition	V_{CC} (V)	Ta = 25°C			Ta = -40 ~ 85°C		Unit
				Min	Typ.	Max.	Min.	Max.	
Propagation Delay Time	t_{pLH}		2.7	–	5.4	12.7	1.0	15.0	ns
	t_{pHL}		3.3 ± 0.3	–	4.5	9.0	1.0	10.0	
Output to Output Skew	t_{osLH}	(Note 1)	2.7	–	–	1.5	–	1.5	ns
	t_{osHL}		3.3 ± 0.3	–	–	1.5	–	1.5	
Input Capacitance	C_{IN}	(Note 2)		–	5	10	–	10	pF
Power Dissipation Capacitance	C_{PD}	(Note 3)		–	24	–	–	–	

Note (1) Parameter guaranteed by design. $t_{osLH} = |t_{pLHm} - t_{pLHn}|$, $t_{osHL} = |t_{pHLm} - t_{pHLn}|$

Note (2) Parameter guaranteed by design.

Note (3) C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per Gate)}$$

Noise Characteristics (Input $t_r = t_f = 3\text{ns}$, $C_L = 50\text{pF}$, $R_L = 500\Omega$)

Parameter	Symbol	Test Condition	V_{CC}	Ta = 25°C		Unit
				Typ.	Max.	
Quiet Output Maximum Dynamic V_{OL}	V_{OLP}	–	3.3	0.3	0.8	V
Quiet Output Minimum Dynamic V_{OL}	V_{OLV}	–	3.3	-0.3	-0.8	V
Minimum High Level Dynamic Input Voltage	V_{IHD}	–	3.3	–	2.0	V
Maximum Low Level Dynamic Input Voltage	V_{ILD}	–	3.3	–	0.8	V